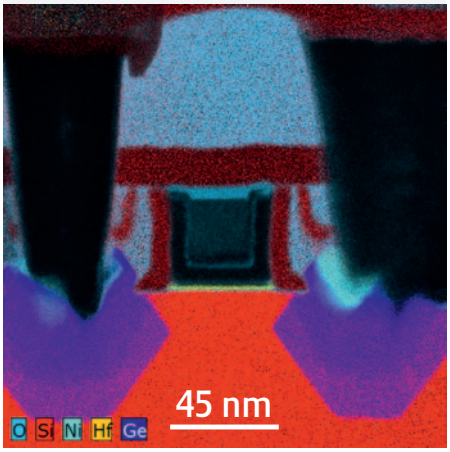
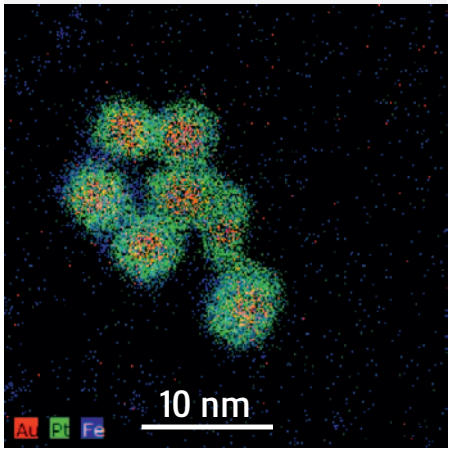
ChemiSTEM™ technology
A revolution in EDX analytics

Large map, all elements



45 nm PMOS structure
600 x 600 pixels
Drift correction applied

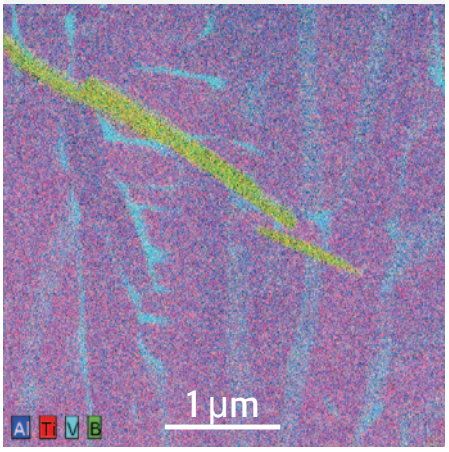
High sensitivity



Au/Pt(Fe) core/shell particles < 5 nm
300 x 300 pixels recorded in < 4 min

Sample courtesy of C. Wang, V. Stamenkovic, N. Markovic and N.J. Zaluzec, Argonne National Laboratory

Light element detection



Boron distribution in TiB/TiAl
512 x 512 pixels recorded in < 5 min
100 µsec dwell time; multiple frames

Sample courtesy of Ohio State University

Tecnai Osiris™

ChemiSTEM™ technology, higher beam current and revolutionary X-ray detection capability:

- **Largest solid angle for EDX detection: 0.9 sr**
- **Ultimate speed: elemental maps in minutes**
- **Highest sensitivity for light elements and low concentrations**

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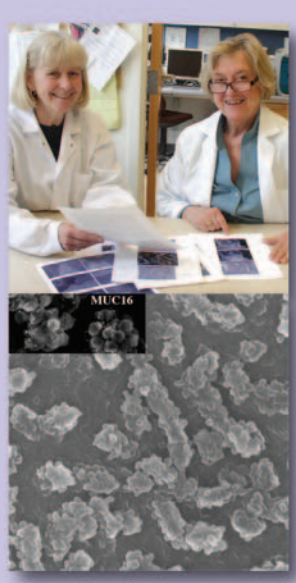
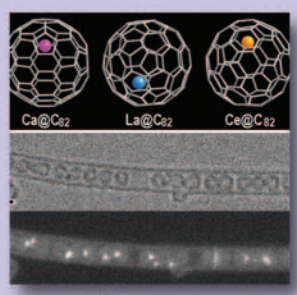
Microscopy in good company.



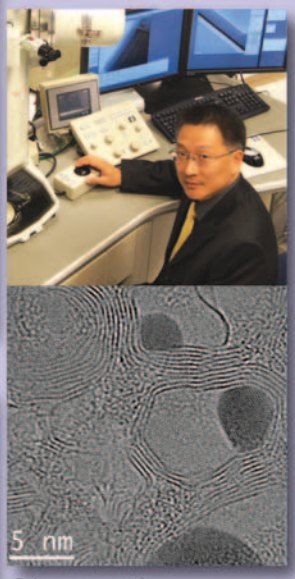
Ann Tisdale, Dr. Ilene Gipson
Schepens Eye Research Institute

Corneal surface



Ca metallofullerene peapod
K. Suenega, AIST

Dr. Moon Kim
University of Texas - Dallas



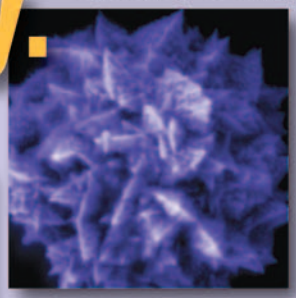
Pd nanocrystals

Dr. Elizabeth Wright
Emory University

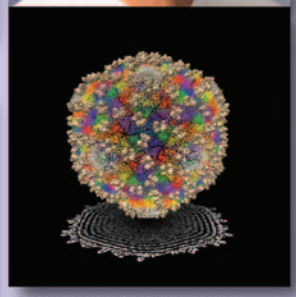
Caulobacter Cb13b1a cells

Tubulin structure 3.5Å – Berkeley Lab
Lowe, Li, Downing, and Nogales

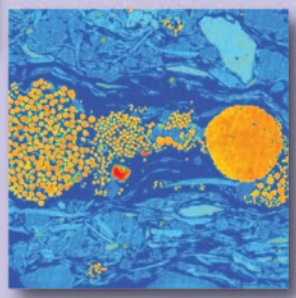
Catalyst - C. Cabrera
University of Puerto Rico



Dr. Wah Chiu
Baylor College of Medicine



Bacteriophage Epsilon 15



Oil shale cross section

The McCrone Group - Tadarida brasiliensis hair

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